

3.3V ECL/PECL/HSTL/LVDS ÷2/4, ÷4/6 Clock Generation Chip

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MC100ES6039

Product Discontinuance Notice – Last Time Buy Expires on (12/19/2013)

DATASHEET

The MC100ES6039 is a low skew $\div 2/4$, $\div 4/6$ clock generation chip designed explicitly for low skew clock generation applications. The internal dividers are synchronous to each other, therefore, the common output edges are all precisely aligned. The device can be driven by either a differential or single-ended ECL or, if positive power supplies are used, LVPECL input signals. In addition, by using the V_{BB} output, a sinusoidal source can be AC coupled into the device.

The common enable (EN) is synchronous so that the internal dividers will only be enabled/disabled when the internal clock is already in the LOW state. This avoids any chance of generating a runt clock pulse on the internal clock when the device is enabled/disabled as can happen with an asynchronous control. The internal enable flip-flop is clocked on the falling edge of the input clock, therefore, all associated specification limits are referenced to the negative edge of the clock input.

Upon startup, the internal flip-flops will attain a random state; therefore, for systems which utilize multiple ES6039s, the master reset (MR) input must be asserted to ensure synchronization. For systems which only use one ES6039, the MR pin need not be exercised as the internal divider design ensures synchronization between the $\div 2/4$ and the $\div 4/6$ outputs of a single device. All V_{CC} and V_{EE} pins must be externally connected to power supply to guarantee proper operation.

The 100ES Series contains temperature compensation.

Features

- Maximum Frequency >1.0 GHz Typical
- 50 ps Output-to-Output Skew
- PECL Mode Operating Range: V_{CC} = 3.135 V to 3.8 V with V_{EE} = 0 V
- ECL Mode Operating Range: V_{CC} = 0 V with V_{EE} = -3.135 V to -3.8 V
- · Open Input Default State
- · Synchronous Enable/Disable
- · Master Reset for Synchronization of Multiple Chips
- V_{BB} Output
- · LVDS and HSTL Input Compatible
- 20-Lead Pb-Free Package Available

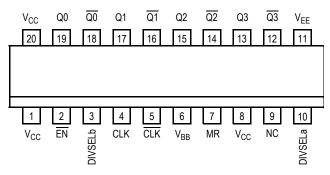


DW SUFFIX 20-LEAD SOIC PACKAGE CASE 751D-07



EG SUFFIX 20-LEAD SOIC PACKAGE Pb-FREE PACKAGE CASE 751D-07

ORDERING INFORMATION						
Device	Package					
MC100ES6039DW	SO-20					
MC100ES6039DWR2	SO-20					
MC100ES6039EG	SO-20 (Pb-Free)					
MC100ES6039EGR2	SO-20 (Pb-Free)					



Warning: All V_{CC} and V_{EE} pins must be externally connected to Power Supply to guarantee proper operation.

Figure 1. 20-Lead Pinout (Top View)

Table 1. Pin Description

Pin	Function
CLK ⁽¹⁾ , CLK ⁽¹⁾	ECL Diff Clock Inputs
EN ⁽¹⁾	ECL Sync Enable
MR ⁽¹⁾	ECL Master Reset
V _{BB}	ECL Reference Output
Q0, Q1, Q0, Q1	ECL Diff ÷2/4 Outputs
Q2, Q3, Q2 , Q3	ECL Diff ÷4/6 Outputs
DIVSELa ⁽¹⁾	ECL Freq. Select Input ÷2/4
DIVSELb ⁽¹⁾	ECL Freq. Select Input ÷4/6
V _{CC}	ECL Positive Supply
V _{EE}	ECL Negative Supply
NC	No Connect

1. Pins will default low when left open.

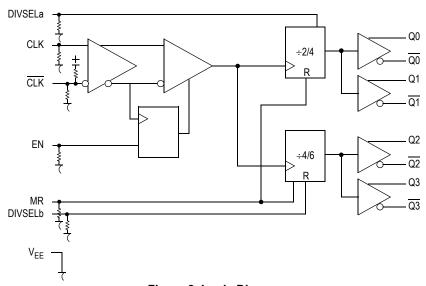


Figure 2. Logic Diagram

Table 2. Function Tables

CLK	EN	MR	Function
Z	L	L	Divide
ZZ	Н	L	Hold Q0:3
X	X	Н	Reset Q0:3

X = Don't Care

Z = Low-to-High Transition

ZZ = High-to-Low Transition

DIVSELa	Q0:1 Outputs
L	Divide by 2
Н	Divide by 4
DIVSELb	Q2:3 Outputs
L	Divide by 4
Н	Divide by 6

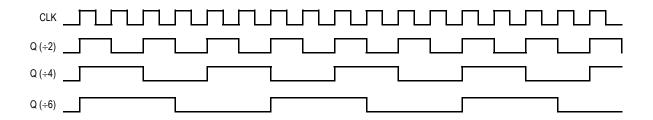


Figure 3. Timing Diagram

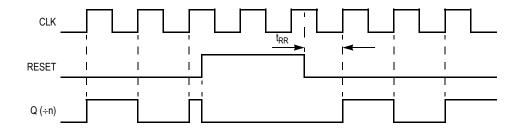


Figure 4. Timing Diagram

Table 3. Attributes

Characteristics	Value	
Internal Input Pulldown Resistor		75 kΩ
Internal Input Pullup Resistor	75 kΩ	
ESD Protection	Human Body Model Machine Model Charged Device Model	> 4 kV > 200 V > 2 kV

Meets or exceeds JEDEC Spec EIA/JESD78 IC Latchup Test

Table 4. Maximum Ratings⁽¹⁾

Symbol	Parameter	Condition 1	Condition 2	Rating	Units
V _{CC}	PECL Mode Power Supply	V _{EE} = 0 V		3.9	V
V _{EE}	ECL Mode Power Supply	V _{CC} = 0 V		-3.9	V
V _I	PECL Mode Input Voltage ECL Mode Input Voltage	V _{EE} = 0 V V _{CC} = 0 V	$\begin{array}{c} V_I \leq V_{CC} \\ V_I \geq V_{EE} \end{array}$	3.9 -3.9	V V
l _{out}	Output Current	Continuous Surge		50 100	mA mA
I _{BB}	V _{BB} Sink/Source			± 0.5	mA
T _A	Operating Temperature Range			-40 to +85	°C
T _{stg}	Storage Temperature Range			-65 to +150	°C
$\theta_{\sf JA}$	Thermal Resistance (Junction-to-Ambient)	0 LFPM 500 LFPM	20 SOIC 20 SOIC	TBD TBD	°C/W

^{1.} Maximum Ratings are those values beyond which device damage may occur.

Table 5. DC Characteristics ($V_{CC} = 0 \text{ V}$, $V_{EE} = -3.8 \text{ V}$ to -3.135 V or $V_{CC} = 3.135 \text{ V}$ to 3.8 V, $V_{EE} = 0 \text{ V}$)⁽¹⁾

Symbol	Characteristic		–40 °C			Unit			
Symbol	Gilalacteristic	Min	Тур	Max	Min	Тур	Max	Unit	
I _{EE}	Power Supply Current		35	60		35	60	mA	
V _{OH}	Output HIGH Voltage ⁽²⁾	V _{CC} –1150	V _{CC} –1020	V _{CC} -800	V _{CC} –1200	V _{CC} –970	V _{CC} –750	mV	
V _{OL}	Output LOW Voltage ⁽²⁾	V _{CC} –1950	V _{CC} –1620	V _{CC} –1250	V _{CC} –2000	V _{CC} -1680	V _{CC} –1300	mV	
V _{IH}	Input HIGH Voltage (Single-Ended)	V _{CC} –1165		V _{CC} -880	V _{CC} –1165		V _{CC} –880	mV	
V _{IL}	Input LOW Voltage (Single-Ended)	V _{CC} –1810		V _{CC} -1475	V _{CC} –1810		V _{CC} –1475	mV	
V _{BB}	Output Reference Voltage	V _{CC} –1400		V _{CC} –1200	V _{CC} -1400		V _{CC} –1200	mV	
V _{PP}	Differential Input Voltage ⁽³⁾	0.12		1.4	0.12		1.4	V	
V _{CMR}	Differential Cross Point Voltage ⁽⁴⁾	V _{EE} +0.2		V _{CC} -0.7	V _{EE} +0.2		V _{CC} -0.7	V	
I _{IH}	Input HIGH Current			150			150	μΑ	
I _{IL}	Input LOW Current	-200			-200			μΑ	

^{1.} MC100ES6139 circuits are designed to meet the DC specifications shown in the above table after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse airflow greater than 500 lfpm is maintained.

^{2.} All loading with 50 Ω to $\mbox{V}_{\mbox{CC}}\mbox{--}2.0$ volts.

^{3.} V_{PP} (DC) is the minimum differential input voltage swing required to maintain device functionality.

^{4.} V_{CMR} (DC) is the crosspoint of the differential input signal. Functional operation is obtained when the crosspoint is within the V_{CMR} (DC) range and the input swing lies within the V_{PP} (DC) specification.

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Cumbal	Characteristic		-40°C		25°C			85°C			Unit	
Symbol			Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Ollit
f _{max}	Maximum Frequenc	у		> 1			> 1			> 1		GHz
t _{PLH} , t _{PHL}	Propagation Delay CLK, Q (Diff) MR, Q		575 500		875 850	575 500		875 850	575 500		875 850	ps ps
t _{RR}	Reset Recovery		200	100		200	100		200	100		ps
t _s	Setup Time	EN, CLK DIVSEL, CLK	200 400	120 180		200 400	120 180		200 400	120 180		ps ps
t _h	Hold Time	CLK, EN CLK, DIVSEL	100 200	50 140		100 200	50 140		100 200	50 140		ps ps
t _{PW}	Minimum Pulse Wid	ith MR	550	450		550	450		550	450		ps
t _{SKEW}	Within Device Skew Q, Q @ Sa Device-to-Device S	me Frequency			80 50 300			80 50 300			80 50 300	ps ps ps
t _{JITTER}	Cycle-to-Cycle Jitte	r (RMS 1σ)			1			1			1	ps
V_{PP}	Input Voltage Swing	g (Differential)	150		1400	150		1400	150		1400	mV
V_{CMR}	Differential Cross P	oint Voltage	V _{EE} +0.2		V _{CC} -1.1	V _{EE} +0.2		V _{CC} -1.1	V _{EE} +0.2		V _{CC} -1.1	V
t _r t _f	Output Rise/Fall Tir (20% – 80%)	mes Q, \overline{Q}	50		300	50		300	50		300	ps

Table 6. AC Characteristics ($V_{CC} = 0 \text{ V}, V_{EE} = -3.8 \text{ V} \text{ to } -3.135 \text{ V} \text{ or } V_{CC} = 3.135 \text{ V} \text{ to } 3.8 \text{ V}, V_{EE} = 0 \text{ V})$ ⁽¹⁾

^{2.} Skew is measured between outputs under identical transitions. Duty cycle skew is defined only for differential operation when the delays are measured from the cross point of the inputs to the cross point of the outputs.

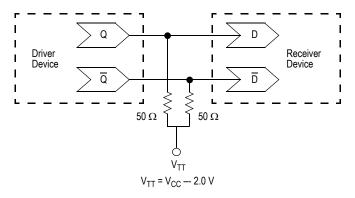
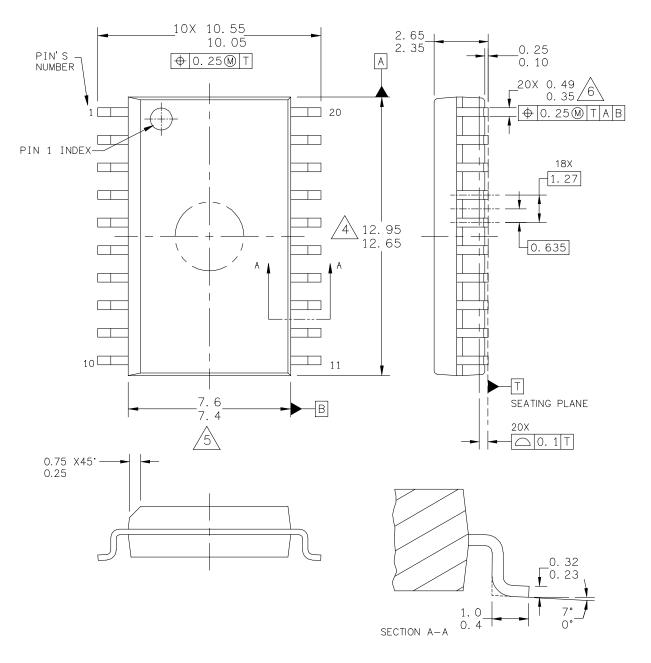


Figure 5. Typical Termination for Output Driver and Device Evaluation

^{1.} Measured using a 750 mV source, 50% duty cycle clock source. All loading with 50 Ω to V_{CC} –2.0 V.

PACKAGE DIMENSIONS



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TITLE:		DOCUMENT NO): 98ASB42343B	REV: J
20LD SOIC W/B, 1.27 PITCH CASE-OUTLINE		CASE NUMBER	R: 751D−07	23 MAR 2005
CASE-001E1	STANDARD: JE	IDEC MS-013AC		

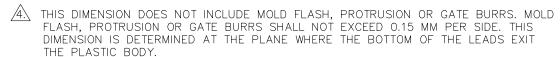
PAGE 1 OF 2

CASE 751D-07 ISSUE J 20-LEAD SOIC PACKAGE

PACKAGE DIMENSIONS

NOTES:

- 1. DIMENSIONS ARE IN MILLIMETERS.
- 2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
- 3. DATUMS A AND B TO BE DETERMINED AT THE PLANE WHERE THE BOTTOM OF THE LEADS EXIT THE PLASTIC BODY.





THIS DIMENSION DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL NOT CAUSE THE LEAD WIDTH TO EXCEED 0.62 mm.

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CNSE OUTEIN		STANDARD: JE	IDEC MS-013AC	

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Revision History Sheet

Rev	Table	Page	Description of Change	Date
3		1	Product Discontinuance Notice – Last Time Buy Expires on (12/19/2013)	2/5/2013

PACKAGE DIMENSIONS

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